

Arrays

CA3227, CA3246

High-Frequency N-P-N Transistor Arrays

For Low-Power Applications at Frequencies up to 1.5 GHz

Features:

- Gain-bandwidth product (f_T) > 3 GHz
- Five transistors on a common substrate

The RCA-CA3227E and CA3246E* consist of five general-purpose silicon n-p-n transistors on a common monolithic substrate. Each of the transistors exhibits a value of f_T in excess of 3 GHz, making them useful from dc to 1.5 GHz. The monolithic construction of these devices provides close electrical and thermal matching of the five transistors.

The CA3227E is supplied in a 16-lead dual-in-line plastic package and the CA3246E is supplied in a 14-lead dual-in-line plastic package.

*Formerly RCA Developmental Nos. TA10854 and TA10855, respectively.

Applications:

- VHF amplifiers
- VHF mixers
- Multifunction combinations - RF/mixer/oscillator
- IF converter
- IF amplifiers
- Sense amplifiers
- Synthesizers
- Synchronous detectors
- Cascade amplifiers

MAXIMUM RATINGS, Absolute-Maximum Values at $T_A=25^\circ\text{C}$:

POWER DISSIPATION, P_D:		
Any one transistor	85 mW
Total Package:		
For T_A up to 75°C	425 mW
For $T_A > 75^\circ\text{C}$ Derate Linearly at	6.67 mW/ $^\circ\text{C}$
AMBIENT TEMPERATURE RANGE:		
Operating	-55 to $+125^\circ\text{C}$
Storage	-65 to $+150^\circ\text{C}$
LEAD TEMPERATURE (DURING SOLDERING):		
At distance $1/16 \pm 1/32$ in. (1.59 ± 0.79 mm) from case for 10 seconds max.	$+265^\circ\text{C}$
The following ratings apply for each transistor in the device.		
Collector-to-Emitter Voltage, V_{CEO}	8 V
Collector-to-Base Voltage, V_{CBO}	12 V
Collector-to-Substrate Voltage, V_{CISO}^{\S}	20 V
Collector Current, I_C	20 mA

[§]The collector of each transistor of these devices is isolated from the substrate by an integral diode. The substrate (terminal 5/CA3227E and terminal 13/CA3246E) must be connected to the most negative point in the external circuit to maintain isolation between transistors and to provide for normal transistor action.

File Number 1345

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STATIC ELECTRICAL CHARACTERISTICS at $T_A=25^\circ\text{C}$

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			Min.	Typ.	Max.	
For Each Transistor:						
Collector-to-Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C=10\ \mu\text{A}, I_E=0$	12	20	—	V
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C=1\ \text{mA}, I_B=0$	8	10	—	V
Collector-to-Substrate Breakdown Voltage	$V_{(BR)CIO}$	$I_{C1}=10\ \mu\text{A}, I_B=0, I_E=0$	20	—	—	V
Emitter-Cutoff-Current*	I_{EBO}	$V_{EB}=4.5\ \text{V}, I_C=0$	—	—	10	μA
Collector-Cutoff-Current	I_{CEO}	$V_{CE}=5\ \text{V}, I_B=0$	—	—	1	μA
Collector-Cutoff-Current	I_{CBO}	$V_{CB}=8\ \text{V}, I_E=0$	—	—	100	nA
DC Forward-Current Transfer Ratio	h_{FE}	$V_{CE}=6\ \text{V}$	$I_C=10\ \text{mA}$	—	110	—
			$I_C=1\ \text{mA}$	40	150	—
			$I_C=0.1\ \text{mA}$	—	150	—
Base-to-Emitter Voltage	V_{BE}	$V_{CE}=6\ \text{V}, I_C=1\ \text{mA}$	0.62	0.71	0.82	V
Collector-to-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C=10\ \text{mA}, I_B=1\ \text{mA}$	—	0.13	0.50	V
Base-to-Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C=10\ \text{mA}, I_B=1\ \text{mA}$	0.74	—	0.94	V

*On small-geometry, high-frequency transistors, it is very good practice never to take the Emitter Base Junction into reverse breakdown. To do so may permanently degrade the h_{FE} . Hence, the use of I_{EBO} rather than $V_{(BR)EBO}$. These devices are also susceptible to damage by electrostatic discharge and transients in the circuits in which they are used. Moreover, CMOS handling procedures should be employed.

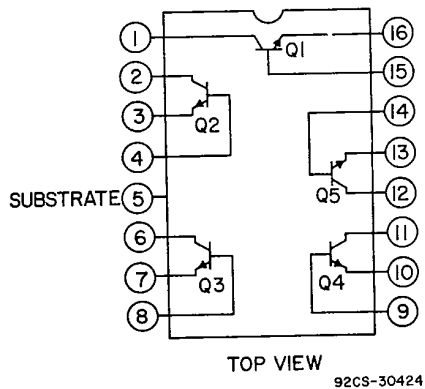


Fig. 1 - Schematic diagram of CA3227

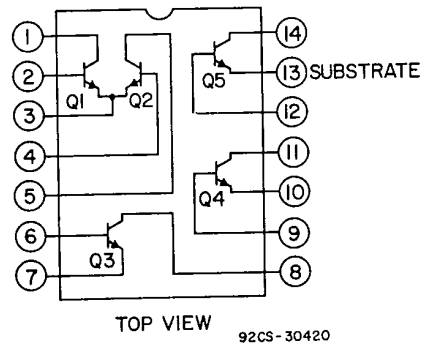


Fig. 2 - Schematic diagram of CA3246

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DYNAMIC ELECTRICAL CHARACTERISTICS at T_A=25°C, 200 MHz, Common Emitter
Typical Values Intended Only for Design Guidance

CHARACTERISTIC	TEST CONDITIONS	TYPICAL VALUES	UNITS	
For Each Transistor				
Input Admittance, $Y_{11} \frac{b_{11}}{g_{11}}$	$I_C=1 \text{ mA},$ $V_{CE}=5 \text{ V}$	4	mmho	
		0.75		
Output Admittance, $Y_{22} \frac{b_{22}}{g_{22}}$		2.7	mmho	
		0.13		
Forward Transfer Admittance, $Y_{21} \frac{Y_{21}}{\theta_{21}}$		29.3	mmho	
		-33		
Reverse Transfer Admittance, $Y_{12} \frac{Y_{12}}{\theta_{12}}$		0.38	mmho	
		-97		
Input Admittance, $Y_{11} \frac{b_{11}}{g_{11}}$		$I_C=10 \text{ mA},$ $V_{CE}=5 \text{ V}$	4.8	mmho
			2.85	
Output Admittance, $Y_{22} \frac{b_{22}}{g_{22}}$	2.75		mmho	
	0.9			
Forward Transfer Admittance, $Y_{21} \frac{Y_{21}}{\theta_{21}}$	95		mmho	
	-62			
Reverse Transfer Admittance, $Y_{12} \frac{Y_{12}}{\theta_{12}}$	0.39		mmho	
	-97			
Small-Signal Forward Current Transfer Ratio h_{21}	$I_C=1 \text{ mA},$ $V_{CE}=5 \text{ V}$		7.1	
	$I_C=10 \text{ mA},$ $V_{CE}=5 \text{ V}$		17	
Typical Capacities @ 1 MHz, Three-Terminal Measurement				
Collector-to-Base Capacitance, C_{CB}	$V_{CB}=6 \text{ V}$	0.3	pF	
Collector-to-Substrate Capacitance, C_{CI}	$V_{CI}=6 \text{ V}$	1.6	pF	
Collector-to-Emitter Capacitance, C_{CE}	$V_{CE}=6 \text{ V}$	0.4	pF	
Emitter-to-Base Capacitance, C_{EB}	$V_{EB}=3 \text{ V}$	0.75	pF	